

## General Description

The AO4601 uses advanced trench technology MOSFETs to provide excellent  $R_{DS(ON)}$  and low gate charge. The complementary MOSFETs may be used to form a level shifted high side switch, and for a host of other applications. Standard Product AO4601 is Pb-free (meets ROHS & Sony 259 specifications). AO4601L is a Green Product ordering option. AO4601 and AO4601L are

## Features

n-channel                      p-channel

 $V_{DS}$  (V) = 30V

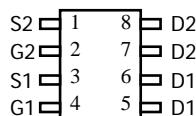
-30V

 $I_D$  = 4.7A ( $V_{GS}$ =10V) -8A ( $V_{GS}$  = -20V)

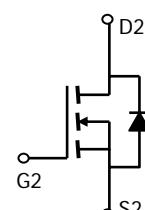
 $R_{DS(ON)}$                        $R_{DS(ON)}$ 

 < 55mΩ ( $V_{GS}$ =10V)      < 18mΩ ( $V_{GS}$  = -20V)

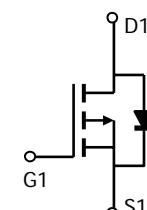
 < 70mΩ ( $V_{GS}$ =4.5V)      < 19mΩ ( $V_{GS}$  = -10V)

 < 110mΩ ( $V_{GS}$  = 2.5V)


SOIC-8



n-channel



p-channel

### Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Max n-channel	Max p-channel	Units
Drain-Source Voltage	$V_{DS}$	30	-30	V
Gate-Source Voltage	$V_{GS}$	$\pm 12$	$\pm 25$	V
Continuous Drain Current <sup>A</sup>	$I_D$	4.7	-8	A
$T_A=70^\circ C$		4	-6.9	
Pulsed Drain Current <sup>B</sup>	$I_{DM}$	30	-50	
Power Dissipation	$P_D$	2	2	W
$T_A=70^\circ C$		1.44	1.44	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	-55 to 150	°C

### Thermal Characteristics: n-channel and p-channel

Parameter	Symbol	Device	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$R_{\theta JA}$	n-ch	52	62.5	°C/W
Steady-State		n-ch	78	110	°C/W
Maximum Junction-to-Lead <sup>C</sup>	$R_{\theta JL}$	n-ch	48	60	°C/W
Steady-State		p-ch	50	62.5	°C/W
Maximum Junction-to-Ambient <sup>A</sup>	$R_{\theta JA}$	p-ch	73	110	°C/W
Steady-State		p-ch	31	40	°C/W
Maximum Junction-to-Lead <sup>C</sup>	$R_{\theta JL}$	p-ch			
Steady-State					

**n-channel MOSFET Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	30			V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS}=24\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			1 5	$\mu\text{A}$
$I_{\text{GSS}}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 12\text{V}$			100	nA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	0.6	1	1.4	V
$I_{\text{D(ON)}}$	On state drain current	$V_{GS}=4.5\text{V}, V_{DS}=5\text{V}$	10			A
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=4\text{A}$ $T_J=125^\circ\text{C}$		45 66	55 80	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_D=3\text{A}$			55 70	$\text{m}\Omega$
		$V_{GS}=2.5\text{V}, I_D=2\text{A}$			83 110	$\text{m}\Omega$
$g_{\text{FS}}$	Forward Transconductance	$V_{DS}=5\text{V}, I_D=4\text{A}$		8		S
$V_{\text{SD}}$	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.8	1	V
$I_S$	Maximum Body-Diode Continuous Current				2.5	A
<b>DYNAMIC PARAMETERS</b>						
$C_{\text{iss}}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=15\text{V}, f=1\text{MHz}$		390		pF
$C_{\text{oss}}$	Output Capacitance			54.5		pF
$C_{\text{rss}}$	Reverse Transfer Capacitance			41		pF
$R_g$	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		3		$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g$	Total Gate Charge	$V_{GS}=4.5\text{V}, V_{DS}=15\text{V}, I_D=4\text{A}$		0.6		nC
$Q_{\text{gs}}$	Gate Source Charge			1.38		nC
$Q_{\text{gd}}$	Gate Drain Charge			4.34		nC
$t_{\text{D(on)}}$	Turn-On Delay Time	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, R_L=3.75\Omega, R_{\text{GEN}}=6\Omega$		3.3		ns
$t_r$	Turn-On Rise Time			1		ns
$t_{\text{D(off)}}$	Turn-Off Delay Time			21.7		ns
$t_f$	Turn-Off Fall Time			2.1		ns
$t_{\text{rr}}$	Body Diode Reverse Recovery Time	$I_F=4\text{A}, dI/dt=100\text{A}/\mu\text{s}$		12		ns
$Q_{\text{rr}}$	Body Diode Reverse Recovery Charge	$I_F=4\text{A}, dI/dt=100\text{A}/\mu\text{s}$		6.3		nC

A: The value of  $R_{\theta JA}$  is measured with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The value in any given application depends on the user's specific board design. The current rating is based on the  $t \leq 10\text{s}$  thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C. The  $R_{\theta JA}$  is the sum of the thermal impedance from junction to lead  $R_{\theta JL}$  and lead to ambient.

D. The static characteristics in Figures 1 to 6 are obtained using 80  $\mu\text{s}$  pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The SOA curve provides a single pulse rating.

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## N-CHANNEL TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

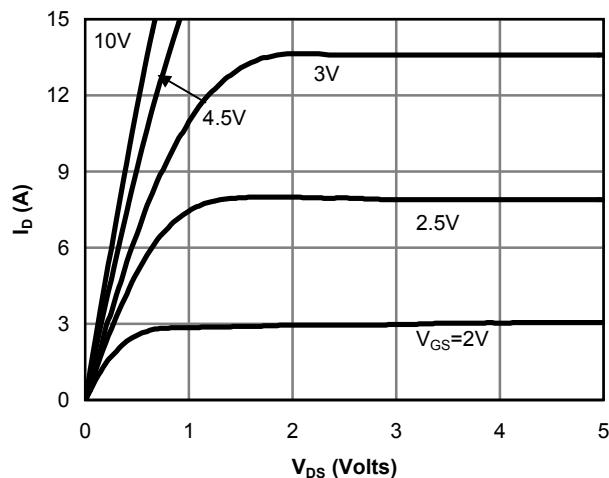


Fig 1: On-Region Characteristics

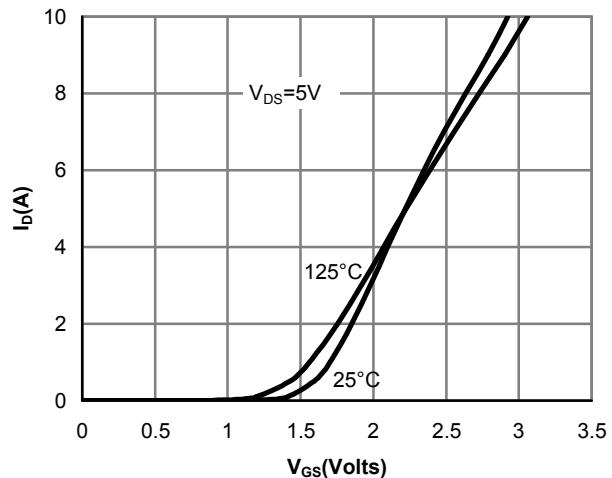


Figure 2: Transfer Characteristics

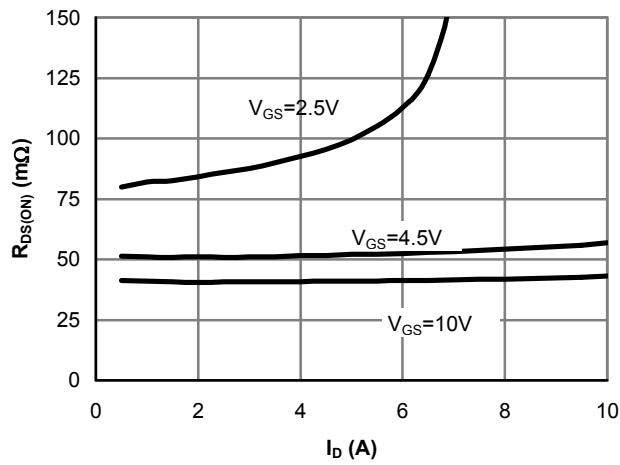


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

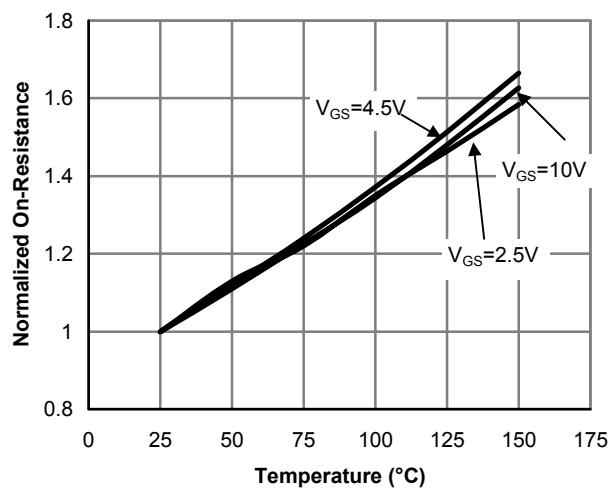


Figure 4: On-Resistance vs. Junction Temperature

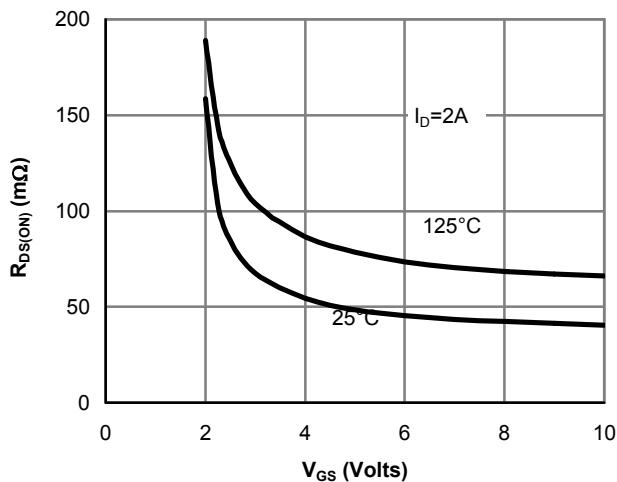


Figure 5: On-Resistance vs. Gate-Source Voltage

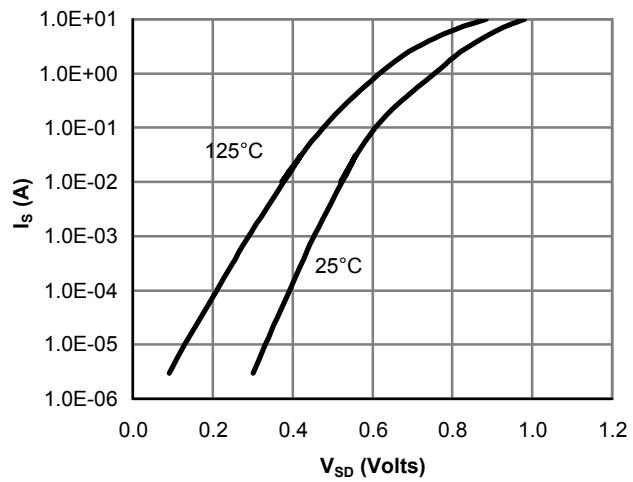


Figure 6: Body-Diode Characteristics

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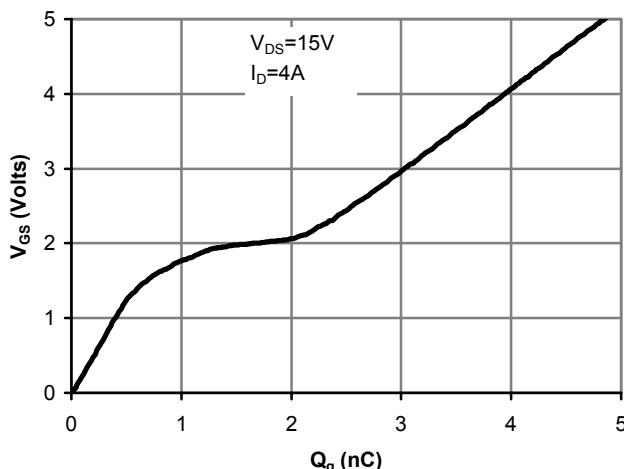


Figure 7: Gate-Charge Characteristics

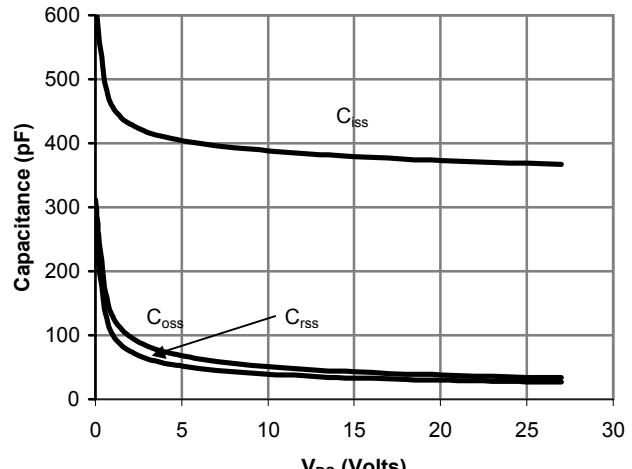


Figure 8: Capacitance Characteristics

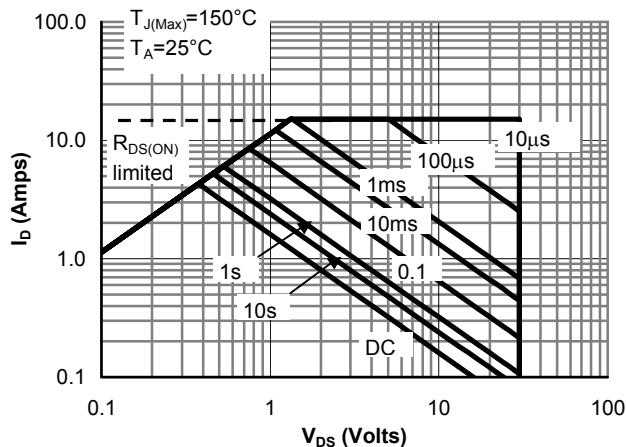


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

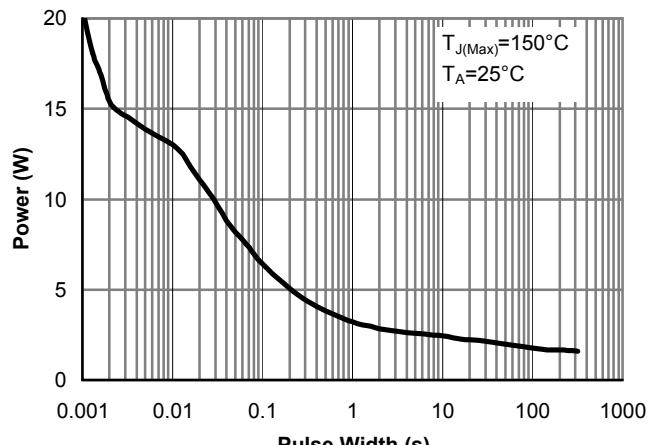


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

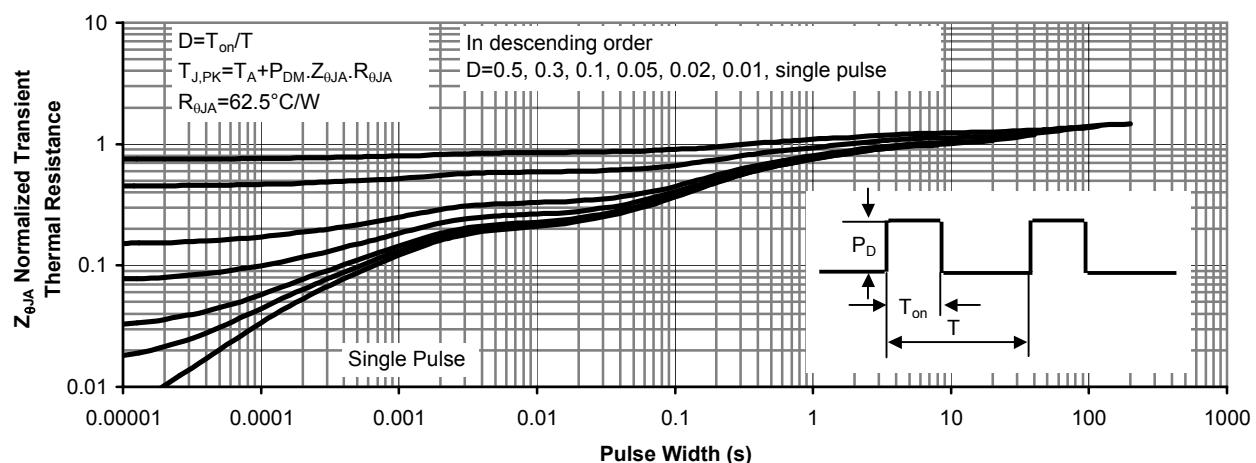


Figure 11: Normalized Maximum Transient Thermal Impedance

**p-channel MOSFET Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=-250\mu\text{A}, V_{GS}=0\text{V}$	-30			V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS}=-24\text{V}, V_{GS}=0\text{V}$			-1	$\mu\text{A}$
		$T_J=55^\circ\text{C}$			-5	
$I_{\text{GSS}}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm25\text{V}$			$\pm100$	nA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=-250\mu\text{A}$	-1.7	-2.5	-3	V
$I_{\text{D(ON)}}$	On state drain current	$V_{GS}=-10\text{V}, V_{DS}=-5\text{V}$	40			A
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=-10\text{V}, I_D=-8\text{A}$		16	19	$\text{m}\Omega$
		$T_J=125^\circ\text{C}$		20.5	25	
		$V_{GS}=-20\text{V}, I_D=-8\text{A}$		15	18	
		$V_{GS}=-4.5\text{V}, I_D=-5\text{A}$		33		$\text{m}\Omega$
$g_{\text{FS}}$	Forward Transconductance	$V_{DS}=-5\text{V}, I_D=-8\text{A}$	16	21		S
$V_{\text{SD}}$	Diode Forward Voltage	$I_S=-1\text{A}, V_{GS}=0\text{V}$		-0.75	-1	V
$I_S$	Maximum Body-Diode Continuous Current				-2.6	A
<b>DYNAMIC PARAMETERS</b>						
$C_{\text{iss}}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=-15\text{V}, f=1\text{MHz}$		2076		pF
$C_{\text{oss}}$	Output Capacitance			503		pF
$C_{\text{rss}}$	Reverse Transfer Capacitance			302		pF
$R_g$	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		2		$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g$	Total Gate Charge	$V_{GS}=-10\text{V}, V_{DS}=-15\text{V}, I_D=-8\text{A}$		39		nC
$Q_{\text{gs}}$	Gate Source Charge			8		nC
$Q_{\text{gd}}$	Gate Drain Charge			11.4		nC
$t_{\text{D(on)}}$	Turn-On Delay Time	$V_{GS}=-10\text{V}, V_{DS}=-15\text{V}, R_L=1.8\Omega, R_{\text{GEN}}=3\Omega$		12.7		ns
$t_r$	Turn-On Rise Time			7		ns
$t_{\text{D(off)}}$	Turn-Off Delay Time			25.2		ns
$t_f$	Turn-Off Fall Time			12		ns
$t_{\text{rr}}$	Body Diode Reverse Recovery Time	$I_F=-8\text{A}, dI/dt=100\text{A}/\mu\text{s}$		32		ns
$Q_{\text{rr}}$	Body Diode Reverse Recovery Charge	$I_F=-8\text{A}, dI/dt=100\text{A}/\mu\text{s}$		26		nC

A: The value of  $R_{\theta JA}$  is measured with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The value in any given application depends on the user's specific board design. The current rating is based on the  $t \leq 10\text{s}$  thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C. The  $R_{\theta JA}$  is the sum of the thermal impedance from junction to lead  $R_{\theta JL}$  and lead to ambient.

D. The static characteristics in Figures 1 to 6,12,14 are obtained using 80  $\mu\text{s}$  pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The SOA curve provides a single pulse rating.

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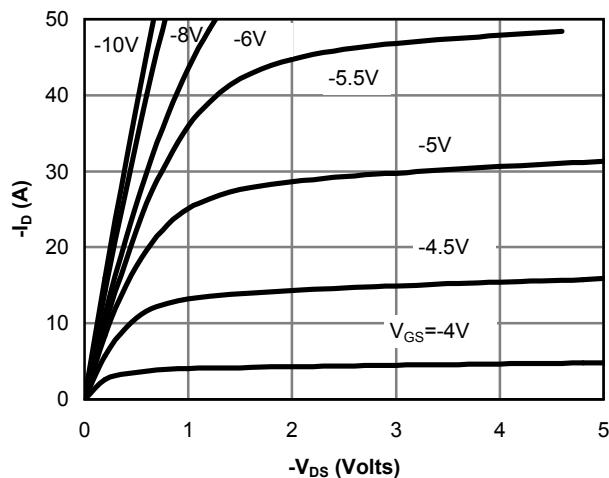


Fig 1: On-Region Characteristics

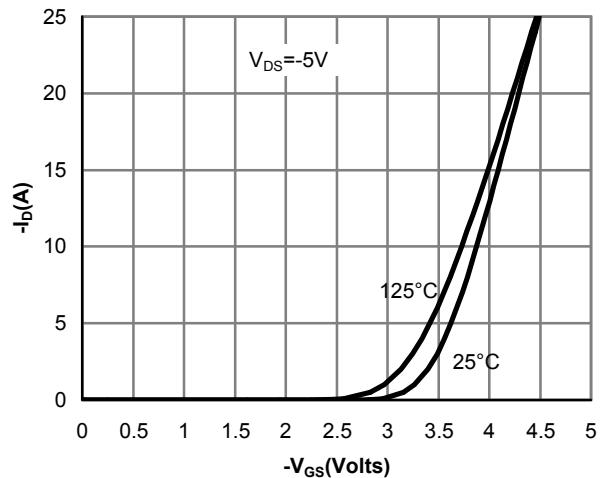


Figure 2: Transfer Characteristics

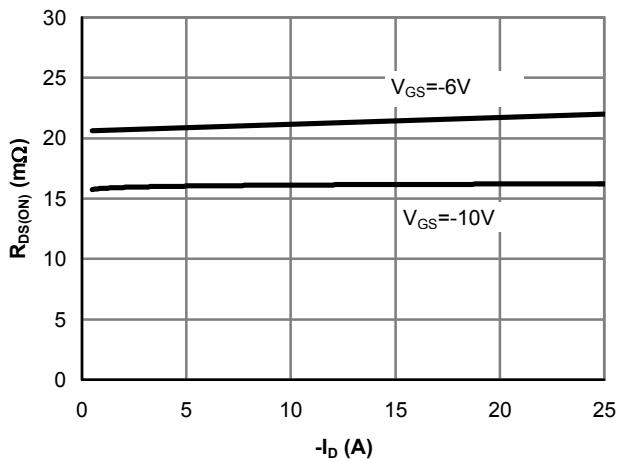


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

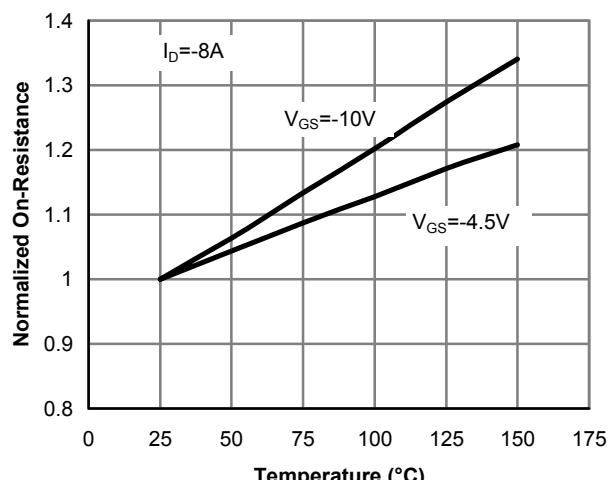


Figure 4: On-Resistance vs. Junction Temperature

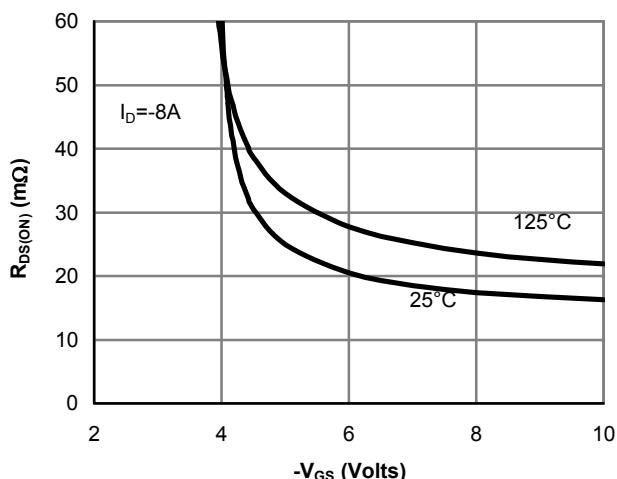


Figure 5: On-Resistance vs. Gate-Source Voltage

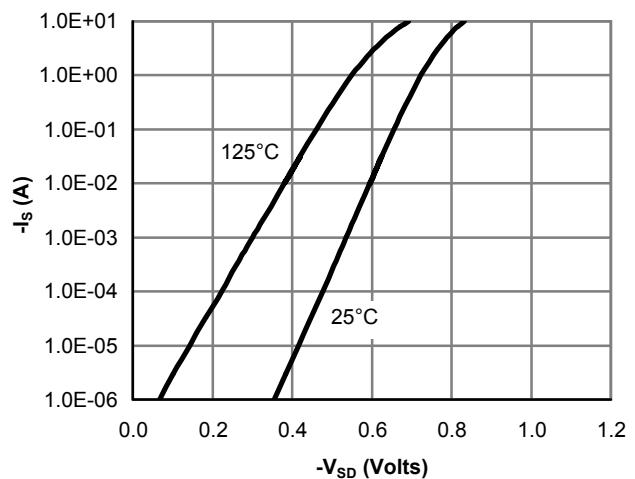


Figure 6: Body-Diode Characteristics

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